SN54ACT534 . . . J OR W PACKAGE

SN74ACT534 . . . DB, DW, N, OR PW PACKAGE

(TOP VIEW)

OE 1Q 2

1D 3

2D 4

 $2\overline{Q}$

 $3\overline{Q}$

3D 🛛 7

4D 🛛 8

40 9

GND I 10

2D

2Q

3Q

3D

4D

5

6

7

8

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20 🛛 V<u>C</u>C

19 8Q

18 8D

17 🛛 7D

16 7 7 Q

14 🛛 6D

13 5D

12 5 <u>0</u>

11 CLK

15 ll 6Q

SN54ACT534 . . . FK PACKAGE

(TOP VIEW)

 \overline{c} $|\overline{c}| = |\overline{c}|_{\overline{c}}^{2}$

9 10 11 12 13

GND

1 20 19

18

16

15

14 6D

8D

7D 17

7Q

6Q

2

- Inputs Are TTL-Voltage Compatible
- **3-State Inverting Outputs Drive Bus Lines** Directly
- Full Parallel Access for Loading
- **EPIC**[™] (Enhanced-Performance Implanted CMOS) 1-µm Process
- **Package Options Include Plastic** Small-Outline (DW), Shrink Small-Outline (DB), Thin Shrink Small-Outline (PW), Ceramic Chip Carriers (FK) and Flatpacks (W), and Standard Plastic (N) and Ceramic (J) DIPs

description

These octal edge-triggered D-type flip-flops feature 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. The devices are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

On the positive transition of the clock (CLK) input, the Q outputs are set to the complements of the logic levels set up at the data (D) inputs.

A buffered output-enable (OE) input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or a high-impedance

state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The highimpedance state and increased drive provide the capability to drive bus lines without need for interface or pullup components.

OE does not affect internal operations of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The SN54ACT534 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74ACT534 is characterized for operation from -40°C to 85°C.

FUNCTION TABLE (each flip-flop)									
	INPUTS		OUTPUT						
OE	CLK	D	Q						
L	\uparrow	Н	L						
L	\uparrow	L	н						
L	H or L	Х							
н	Х	Х	Z						



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logic symbol[†]



logic diagram (positive logic)



To Seven Other Channels

[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[‡]

Supply voltage range, V _{CC}	
Input voltage range, V _I (see Note 1)	
Output voltage range, V _O (see Note 1)	–0.5 V to V _{CC} + 0.5 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	±20 mA
Continuous output current, $I_O (V_O = 0 \text{ to } V_{CC})$	±50 mA
Continuous current through V _{CC} or GND	±200 mA
Maximum power dissipation at $T_A = 55^{\circ}C$ (in still air) (see Note 2	2): DB package 0.6 W
	DW package 1.6 W
	N package 1.3 W
	PW package 0.7 W
Storage temperature range, T _{stg}	–65°C to 150°C

Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils, except for the N package, which has a trace length of zero.



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recommended operating conditions (see Note 3)

		SN54ACT534		SN74ACT534		UNIT
		MIN	MIN MAX		MIN MAX	
Vcc	Supply voltage	4.5	5.5	4.5	5.5	V
VIH	High-level input voltage	2	2	2		V
VIL	Low-level input voltage		0.8		0.8	V
VI	Input voltage	0	Vcc	0	VCC	V
VO	Output voltage	0,	Vcc	0	VCC	V
ЮН	High-level output current	DNC	-24		-24	mA
IOL	Low-level output current	202	24		24	mA
$\Delta t / \Delta v$	Input transition rise or fall rate	Q 0	8	0	8	ns/V
Τ _Α	Operating free-air temperature	-55	125	-40	85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST CONDITIONS	N	т	₄ = 25°C	;	SN54ACT534		SN74ACT534		
PARAMETER	TEST CONDITIONS	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
		4.5 V	4.4	4.49		4.4		4.4		
	I _{OH} = -50 μA	5.5 V	5.4	5.49		5.4		5.4		
Mari	10 24 mA	4.5 V	3.8			3.7		3.76		V
^V ОН	I _{OH} = -24 mA	5.5 V	4.86			4.7		4.76		v
	I _{OH} = -50 mA [†]	5.5 V				3.85				
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V					W	3.85		
	I _{OL} = 50 μA	4.5 V			0.1		0.1		0.1	V
		5.5 V			0.1		0.1		0.1	
Ve	I _{OL} = 24 mA	4.5 V			0.36	6	0.5		0.44	
VOL		5.5 V			0.36) n	0.5		0.44	
	$I_{OL} = 50 \text{ mA}^{\dagger}$	5.5 V				90	1.65			
	I _{OL} = 75 mA [†]	5.5 V				Q			1.65	
I _{OZ}	$V_{O} = V_{CC}$ or GND	5.5 V			±0.25		±5		±2.5	μA
l	$V_{I} = V_{CC}$ or GND	5.5 V			±0.1		±1		±1	μA
ICC	$V_{I} = V_{CC} \text{ or GND}, \qquad I_{O} = 0$	5.5 V			4		80		40	μA
∆lCC‡	One input at 3.4 V, Other inputs at GND or V _{CC}	5.5 V			0.6		1.6		1.5	mA
Ci	$V_{I} = V_{CC} \text{ or } GND$	5 V		4.5						pF

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 2 ms.

[‡]This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V_{CC}.



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timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

		T _A = 25°C		SN54ACT534	SN74ACT534		UNIT
		MIN	MAX	MIN _ MAX	MIN	MAX	
tw	Pulse duration, CLK high or low	3.5		141 50	3.5		ns
t _{su}	Setup time, data before CLK1	3.5		14 14	4		ns
th	Hold time, data after CLK1	1		23	1.5		ns

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T _A = 25°C		SN54ACT534		SN74ACT534		UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
fmax			100		85	N	120		MHz
^t PLH	CLK	-	2.5	11.5	1.5	14	2	12.5	ns
^t PHL	OLK	Q	2	10.5	1.5	13	2	12	115
^t PZH	OE	0	2.5	12	1.5	14	2	12.5	20
^t PZL	ÛE	Q	2	11	1.5	13	2	11.5	ns
^t PHZ	OE	0	1.5	12.5	1.5	14.5	1	13.5	-
^t PLZ	UE	Q	1.5	10.5	2 1.5	11.5	1	10.5	ns

operating characteristics, V_{CC} = 5 V, T_A = 25° C

PARAMETER		TEST CONDITIONS	TYP	UNIT
Cpd	Power dissipation capacitance	$C_L = 50 \text{ pF}, \text{ f} = 1 \text{ MHz}$	40	pF



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PARAMETER MEASUREMENT INFORMATION

NOTES: A. Cl includes probe and jig capacitance.

B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control.

- Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , t_f \leq 2.5 ns, t_f \leq 2.5 ns.

D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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